Substitute for form 1449A/PTO Complete if Known INFORMATION DISCLOSURE 09/069668 **Application Number** STATEMENT BY APPLICANT April 29, 1998 Filing Date Ahn, Kie First Named Inv ntor JAN 2 0 2004 2823 **Group Art Unit** Coleman, W. **Examiner Name** Attorney Docket No: 303.466US1 Sheet 1 of 1

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Electronic Version v18 Stylesheet Version v18.0

> Title of Invention

BIPOLAR TRANSISTORS WITH LOW-RESISTANCE **EMITTER CONTACTS**

Application Number:

09/069668

Confirmation Number:

3628

First Named Applicant:

Kie Ahn

Attorney Docket Number: 303.466US1

Art Unit:

2823

Examiner:

W. Coleman

Search string:

(3932226 or 4169000 or 4442449 or 4670297 or 4855252 or 4857481 or 4959705 or 5040049 or 5148260 or 5158986 or 5187560 or 5241193 or 5268315 or 5308440 or 5334356 or 5391911 or 5454928 or 5458702 or 5501645 or 5516724 or 5516745 or 5539227 or 5563448 or 5593921 or 5705425 or 5710454 or 5753967 or 5757072 or 5796151 or 5796166 or 5798544 or 5798559 or 5847439 or 5861340 or 5891797 or 5920121 or 5925918 or 5925933 or 5930596 or 5930668 or 5942799 or 5960313 or 5989718 or 6025261 or 6080646 or 6150252 or 6157082 or 6180509 or 6211562 or 6245663 or 6265602 or

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Signature

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